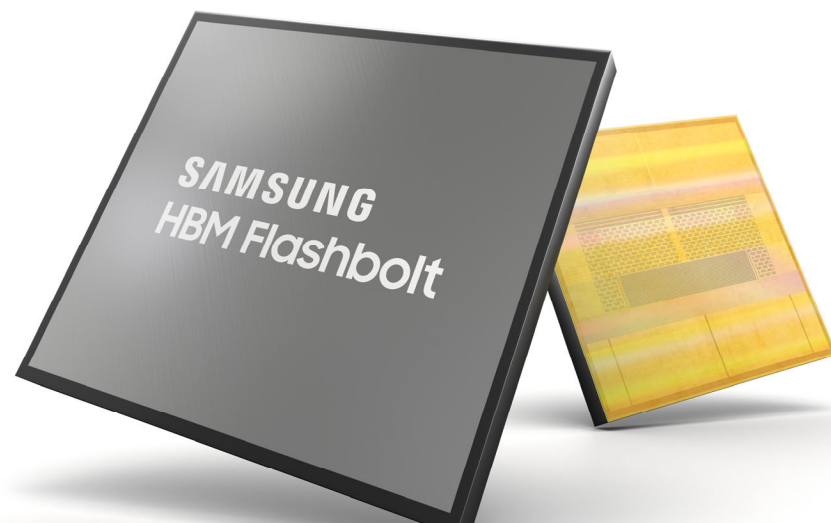


# EE241B : Advanced Digital Circuits

## Lecture 13 – SRAM

**Borivoje Nikolić**



**March 4, 2020, EE Times**

**HBM Flourishes, But HMC Lives.** While high bandwidth memory (HBM) is flourishing, hybrid memory cube (HMC) is finding life in applications that didn't exist when it was first conceived.

# Announcements

- Assignment 2 due on Friday
  - Quiz 2 on Tuesday, March 10
- Please send me links to your project web pages



# Outline

- **Module 4**
  - SRAM margins

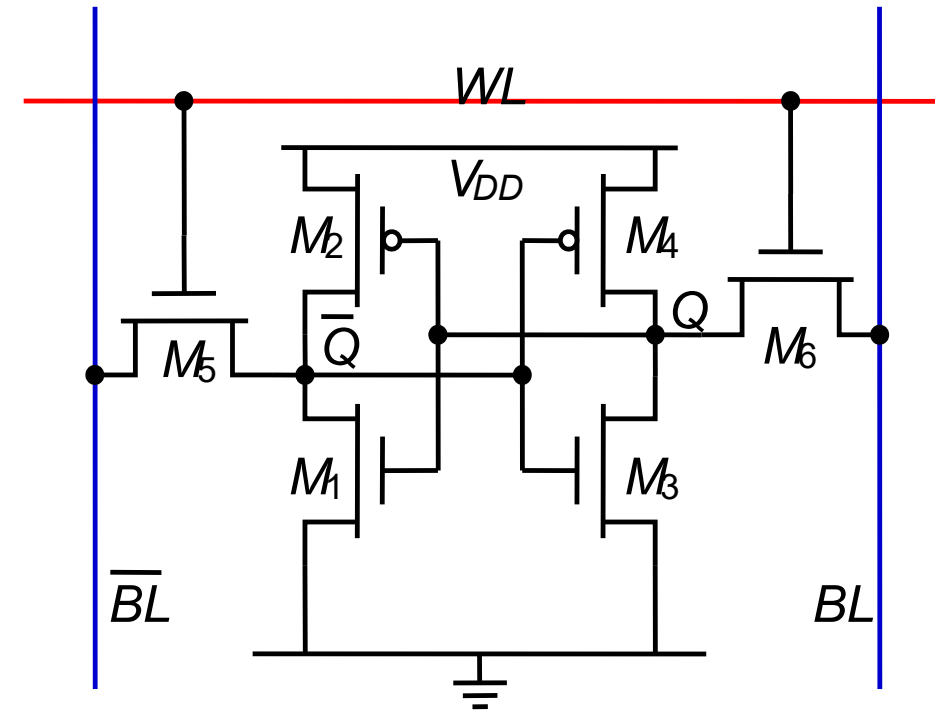
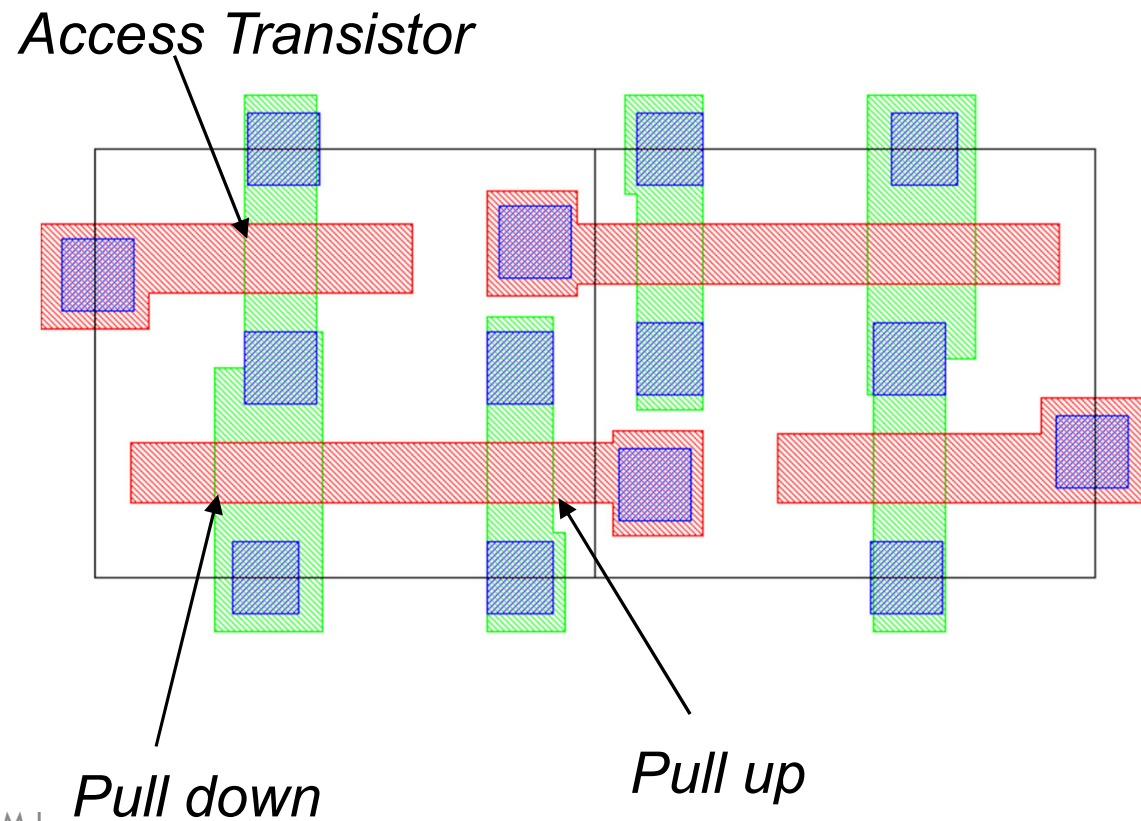


## 4. Memory

### 4.B SRAM Static Retention Margin

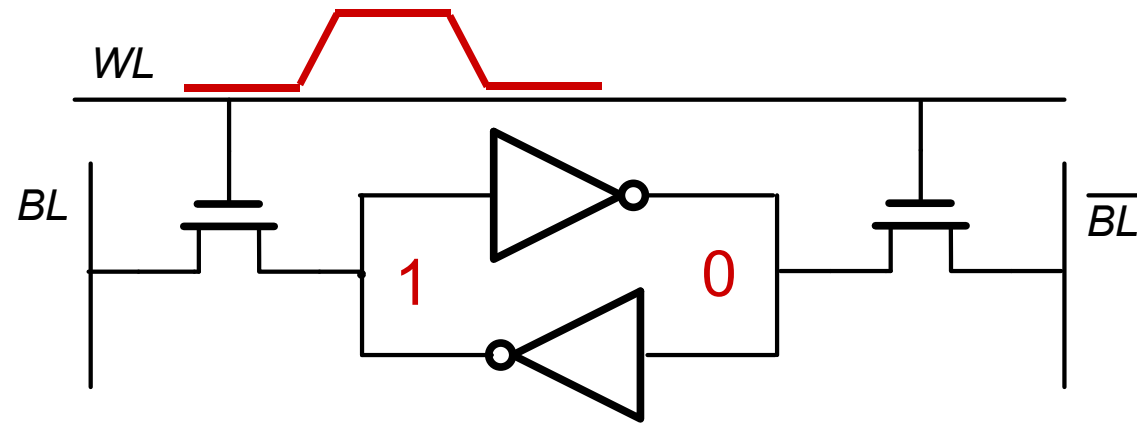
# SRAM Cell/Array

- Hold (retention) stability
- Read stability
- Write stability
- Read access time

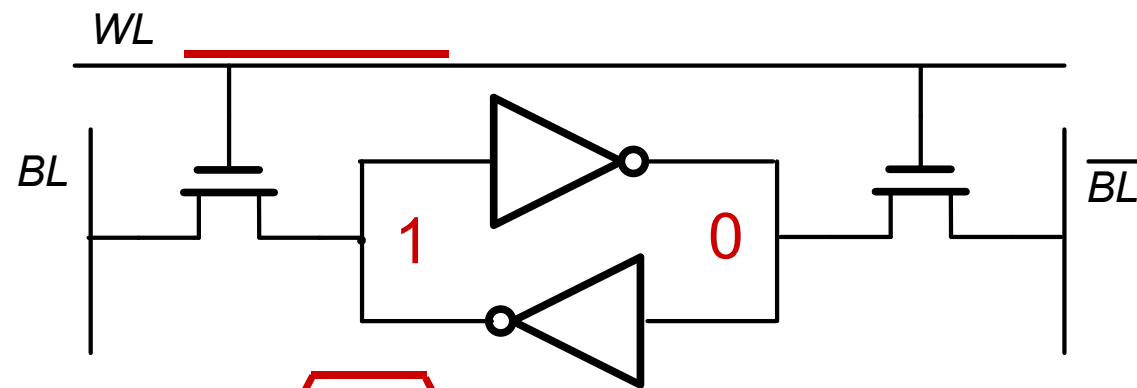


# SRAM Operation

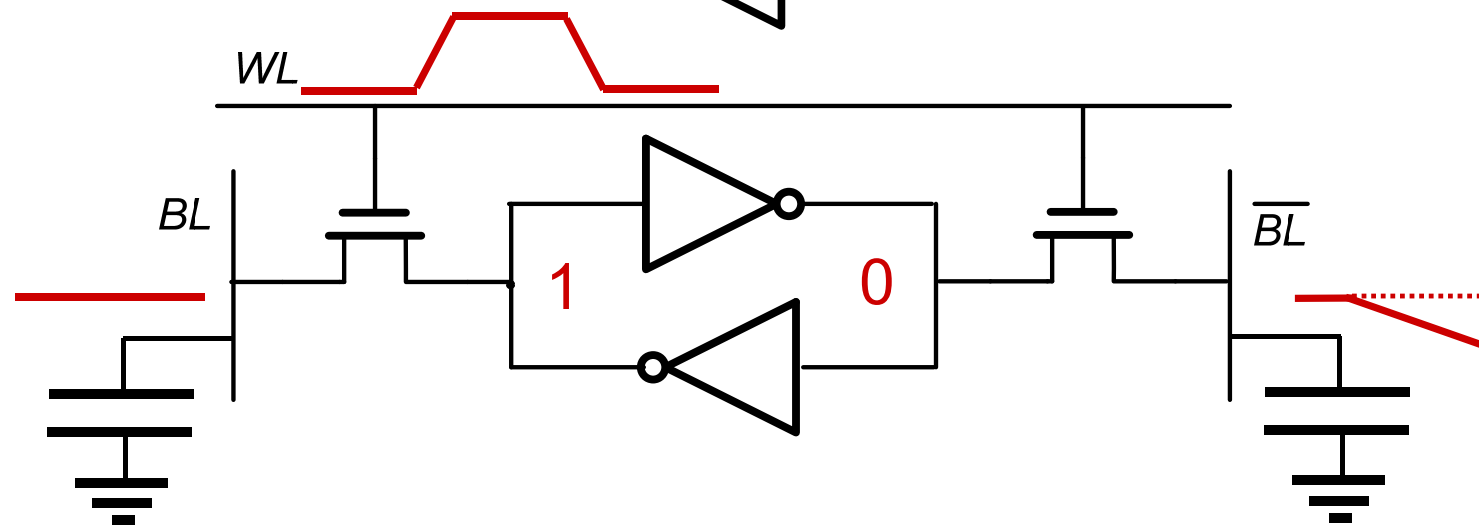
*Write*



*Retention*

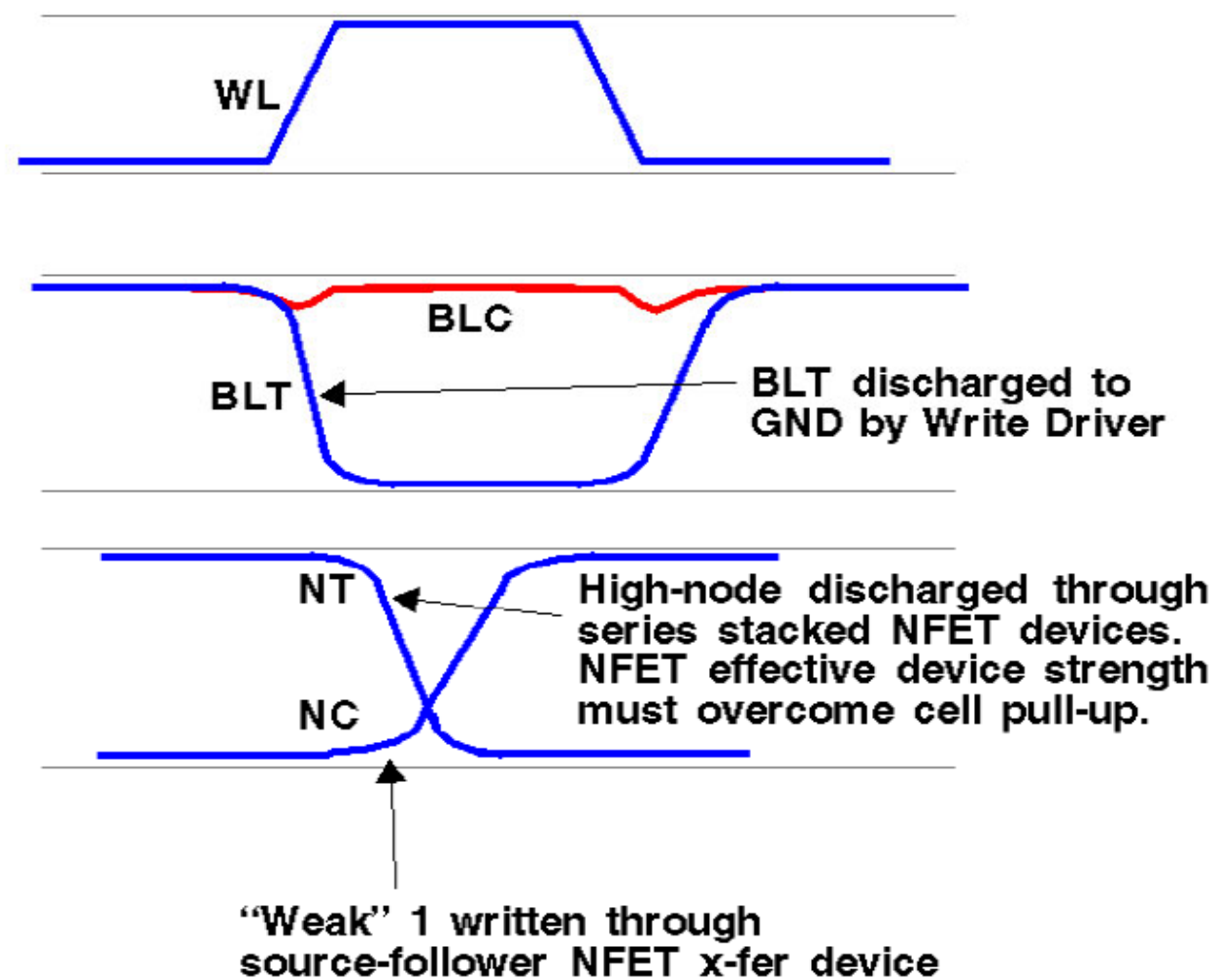
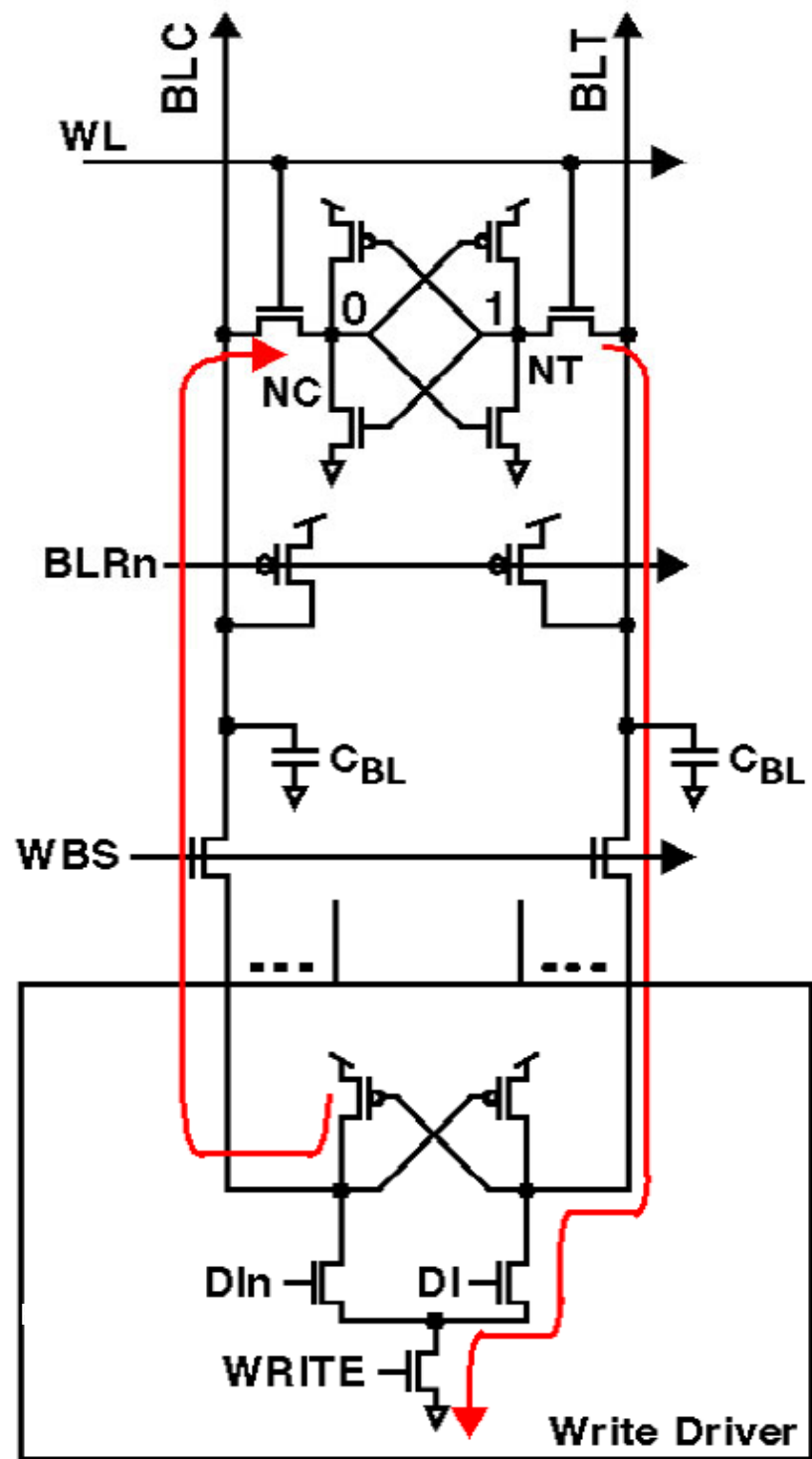


*Read*

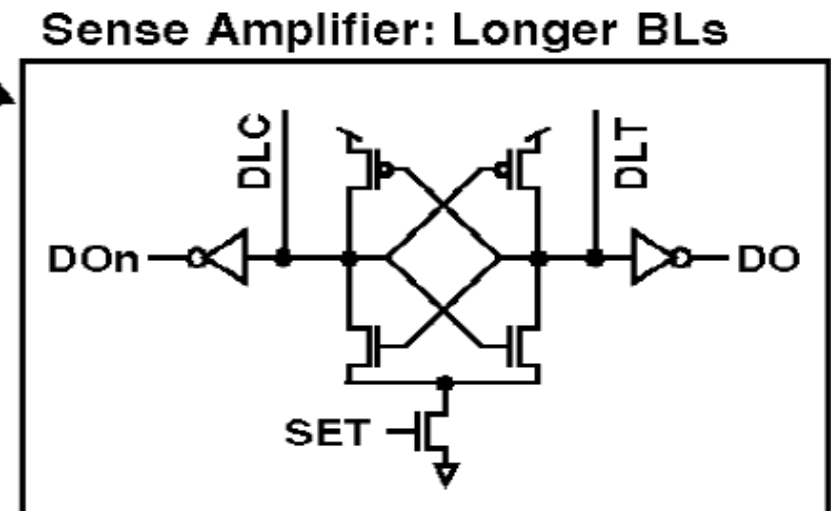
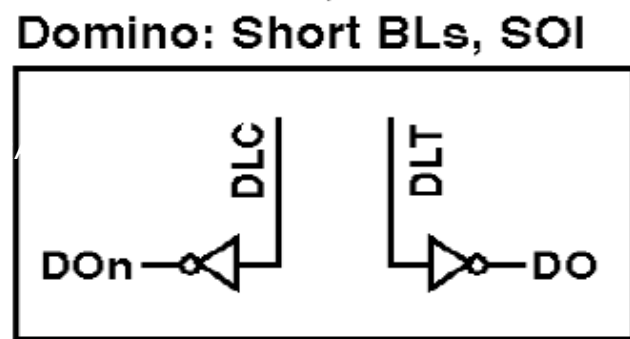
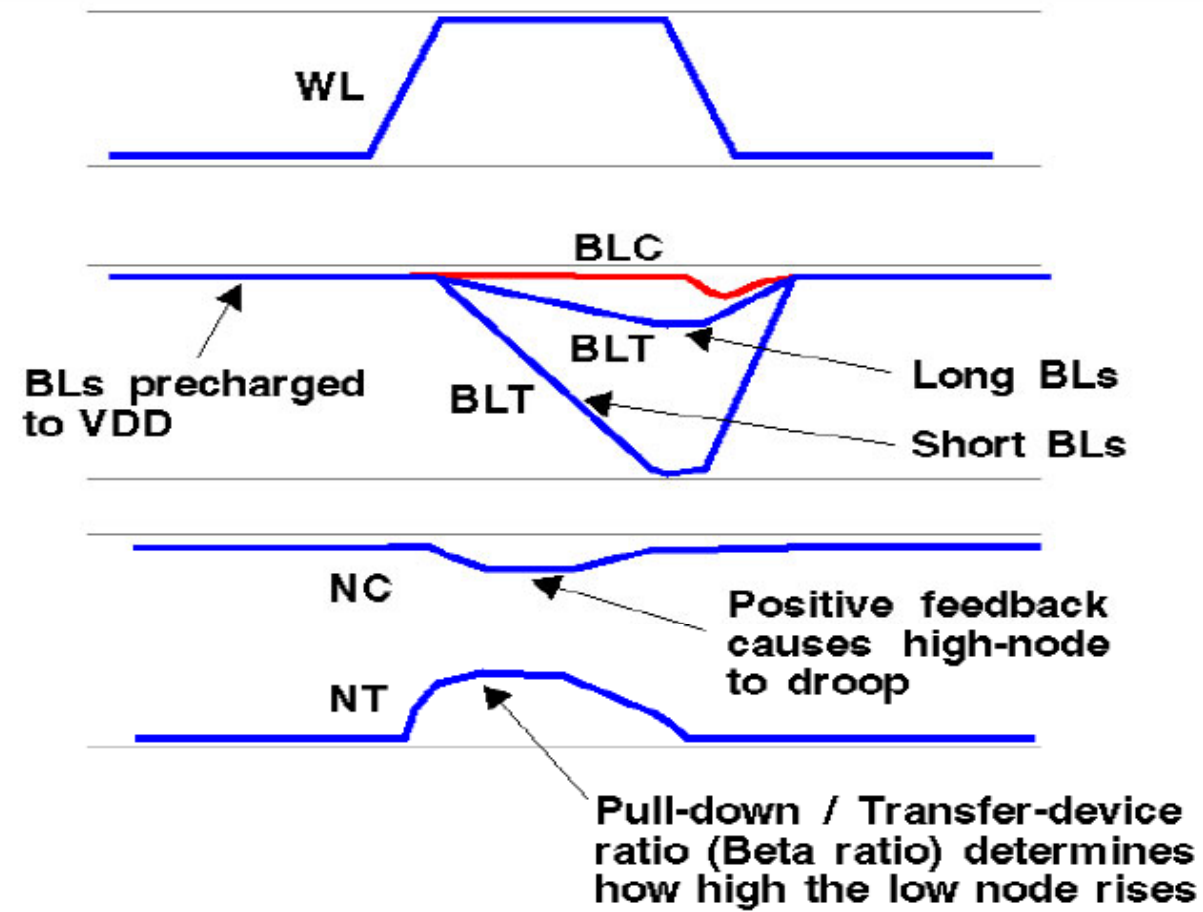
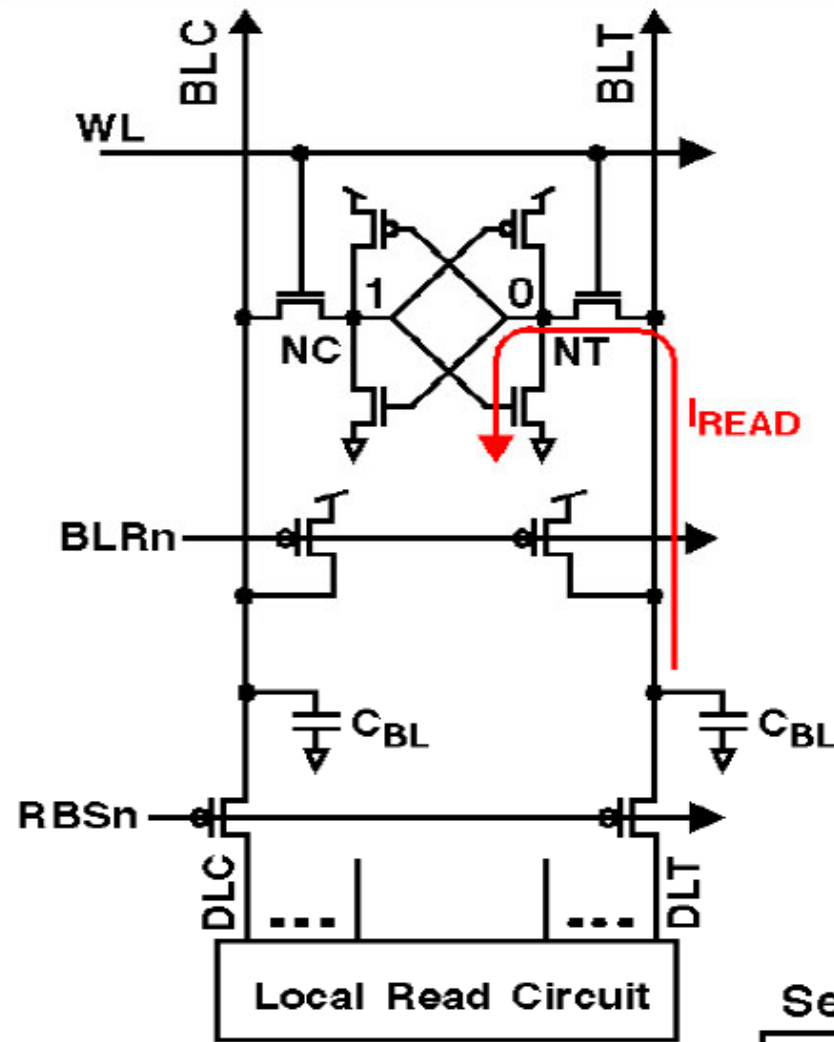




# 6T-SRAM Array Basics – Write Operation

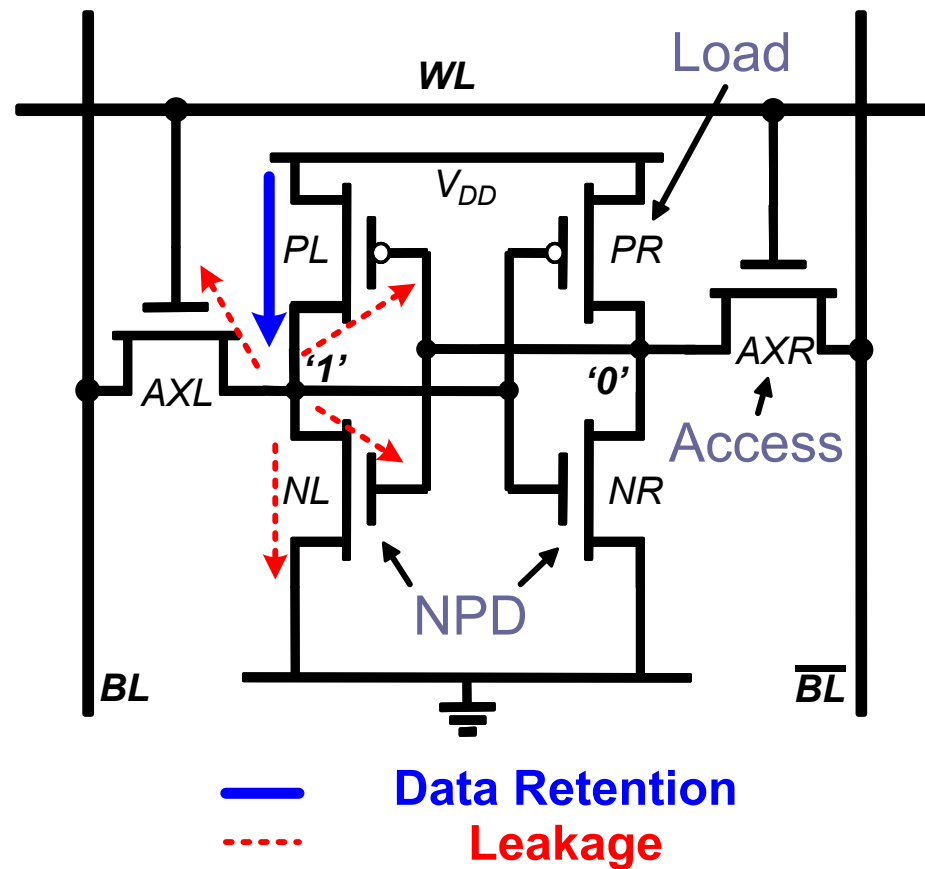


# 6T-SRAM Array Basics – Read Operation

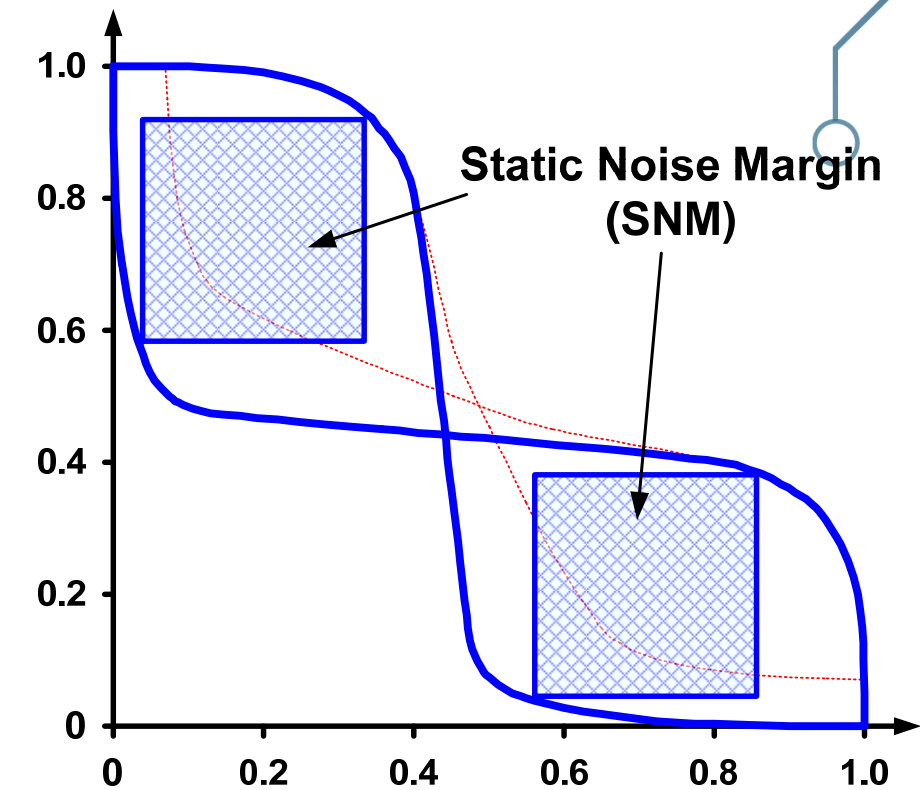




# SRAM Design – Hold (Retention) Stability

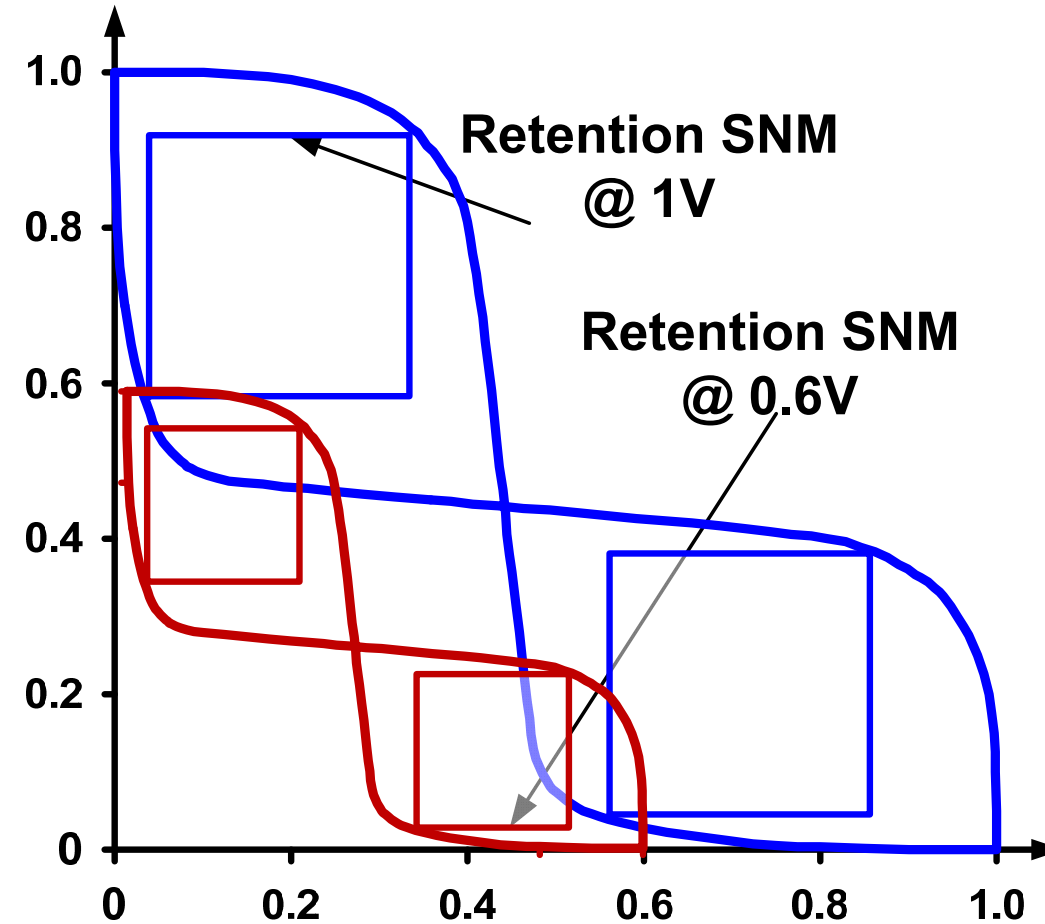
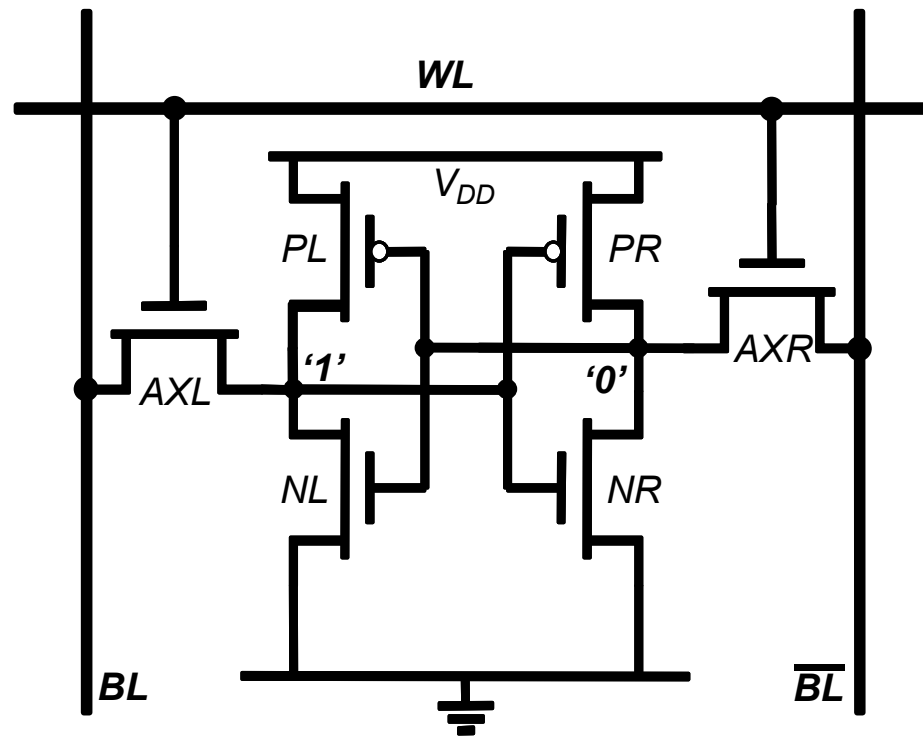


- › Scaling trend:
  - › Increased gate leakage + degraded  $I_{ON}/I_{OFF}$  ratio
  - › Lower  $V_{DD}$  during standby
- › PMOS load devices must compensate for leakage

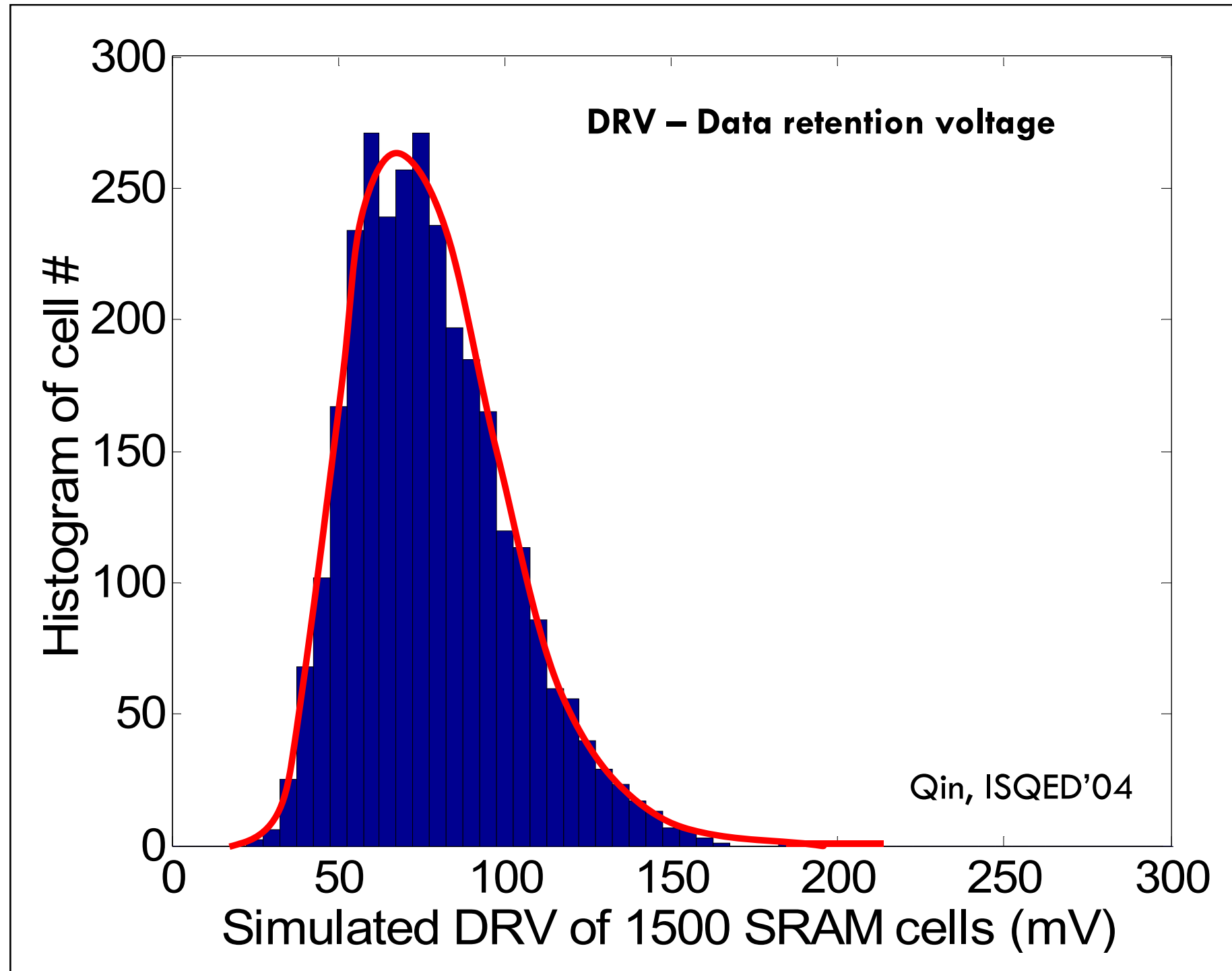


# Retention Stability

- Would like to reduce supply in standby



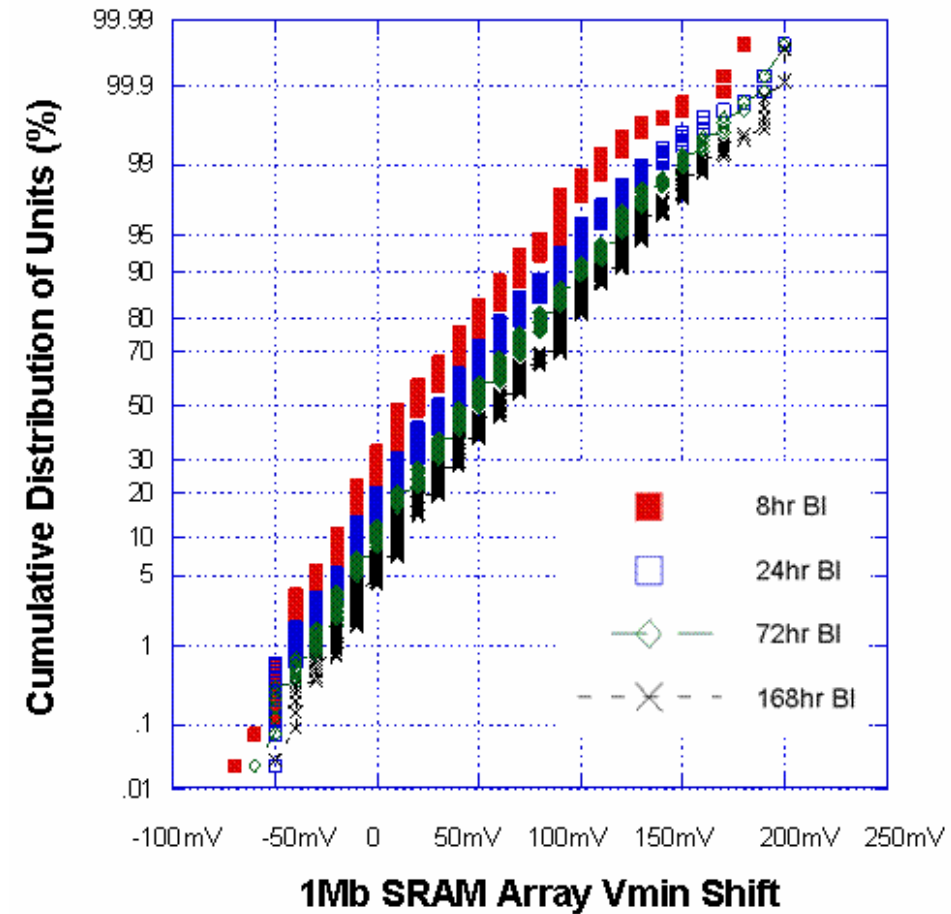
# Monte-Carlo Simulation of DRV Distribution



# Vmin Distribution

- Aggregate minimum operating voltage
- Digital test under supply sweep

1Mb SRAM Array Vmin Shift w/ Burn-In

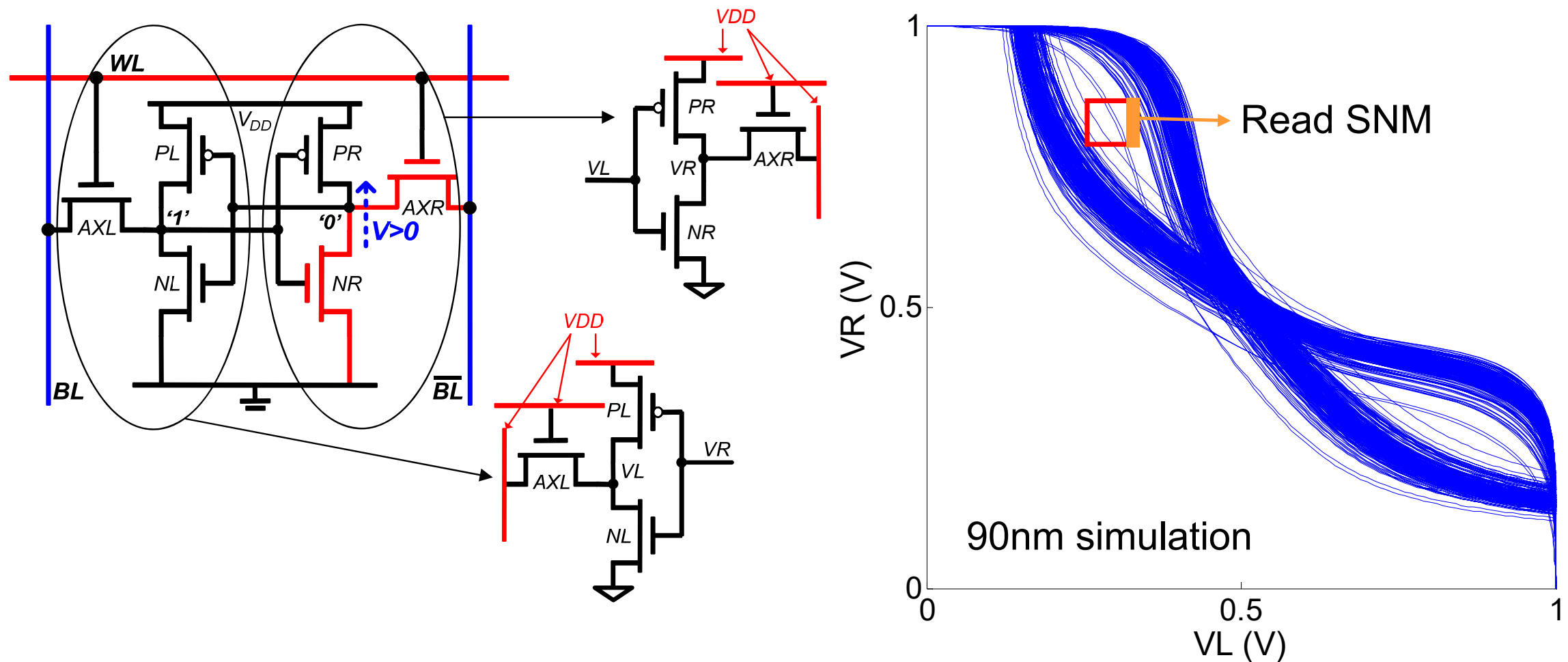


M Ball, IEDM'06



# 4.C Static Read/Write Margins

# Read Stability – Static Noise Margin (SNM)



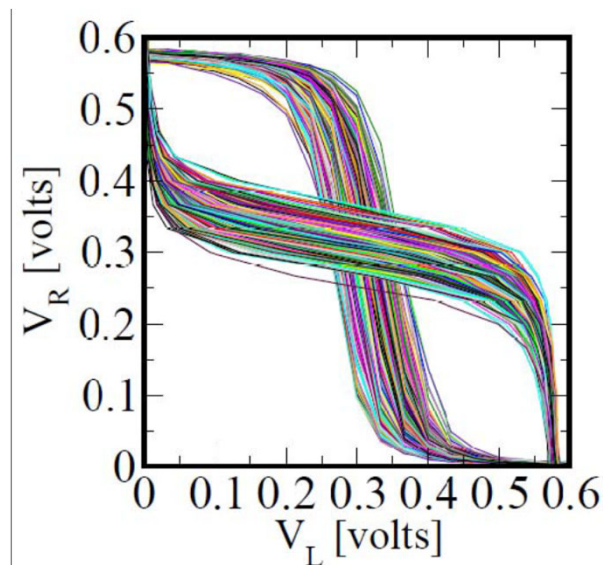
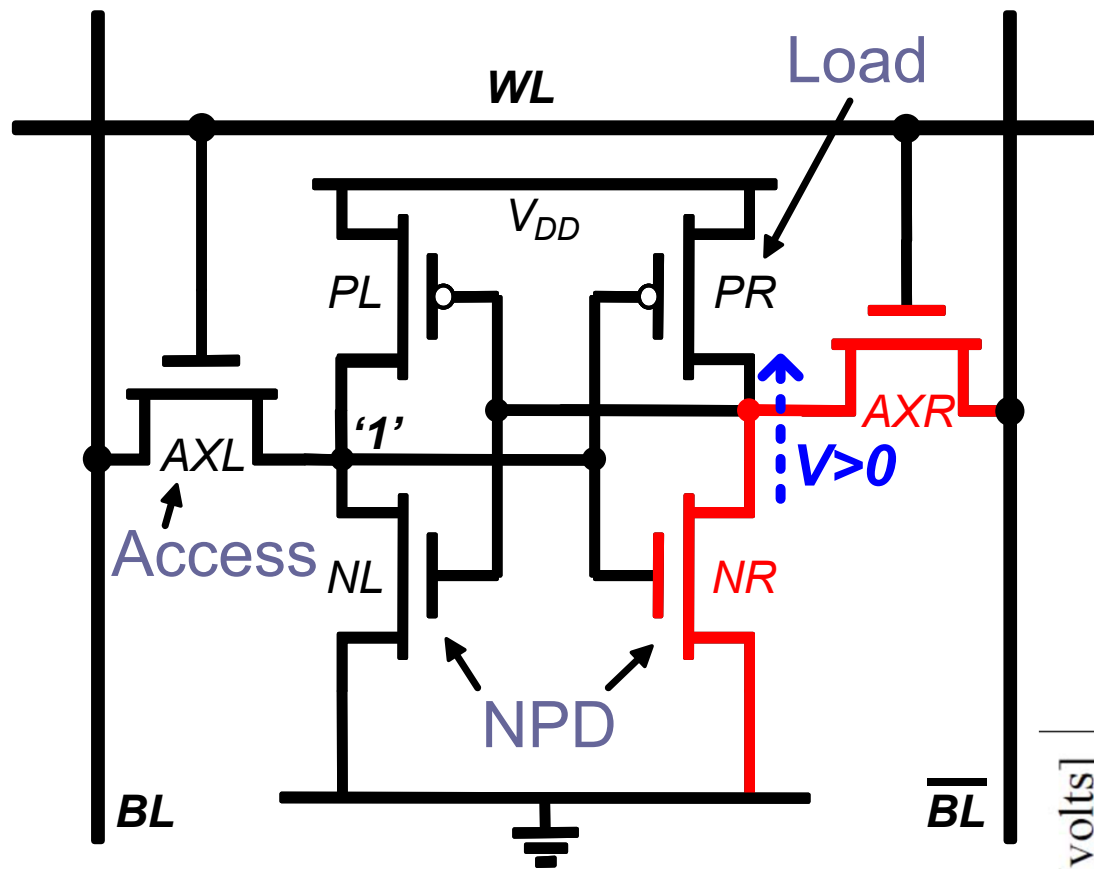
- Read SNM is the contention between the two sides of the cell under read stress.

$$\Delta V_{Th} \propto \frac{1}{C_{ox} \sqrt{WL}}$$

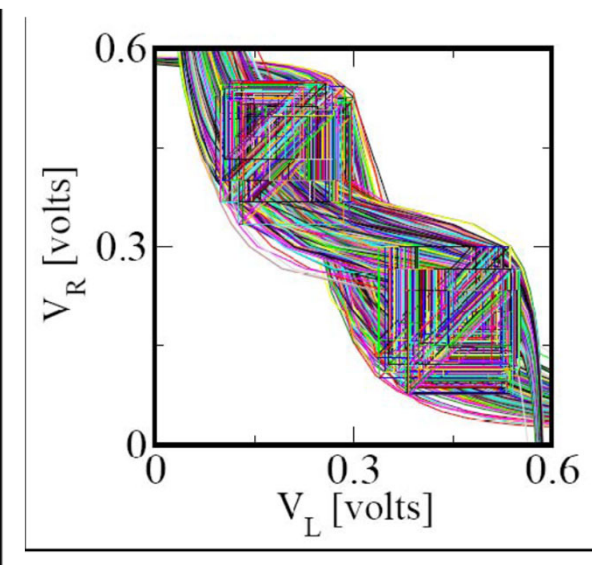
Due to RDF



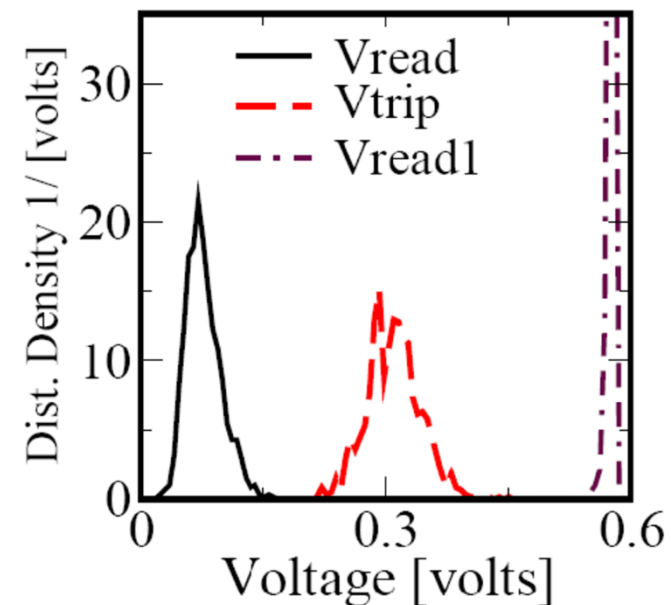
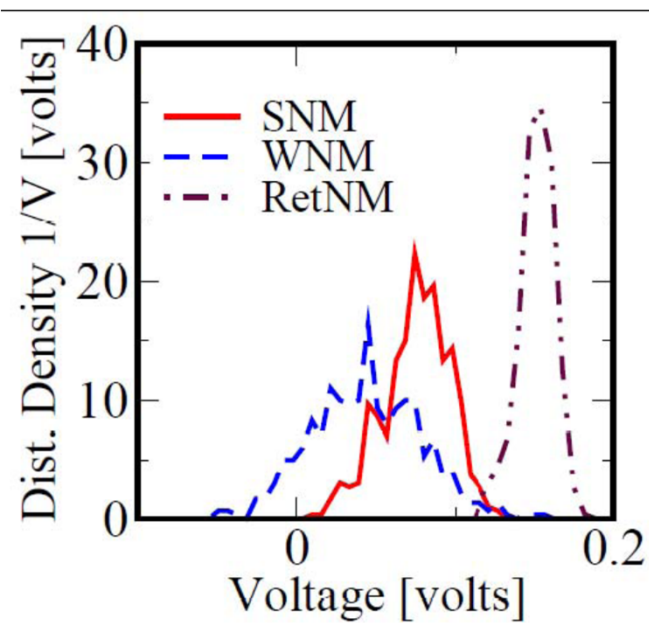
# Read SNM - Measurements



Retention fluctuations



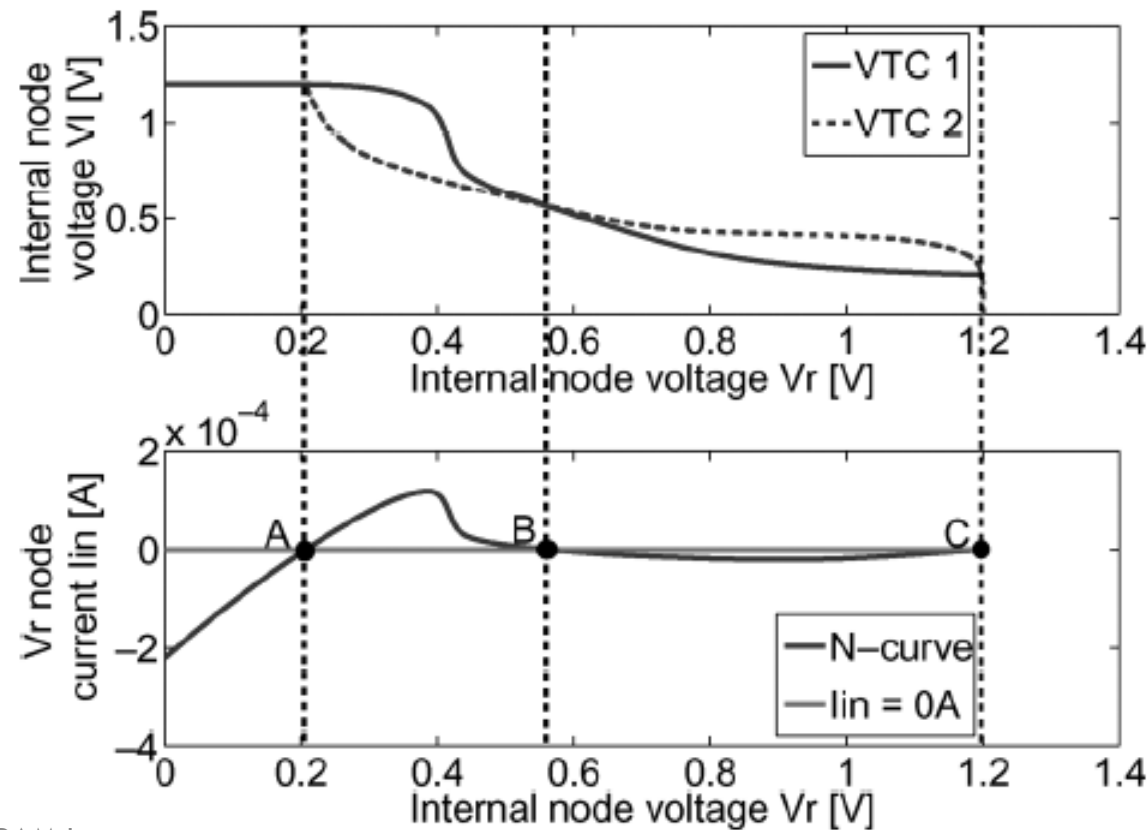
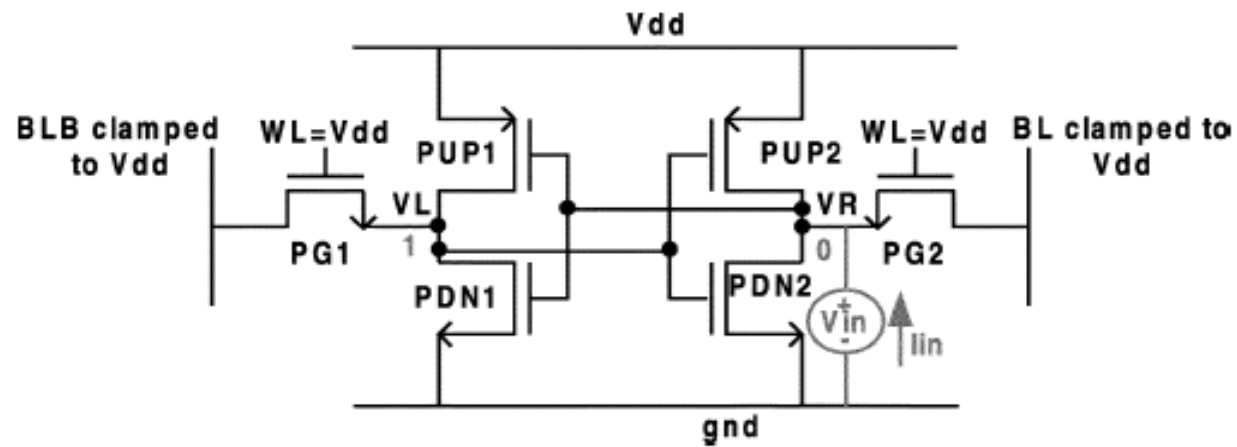
Read Fluctuations



► Read margin vs. retention margin

Bhavnagarwala, IEDM'05

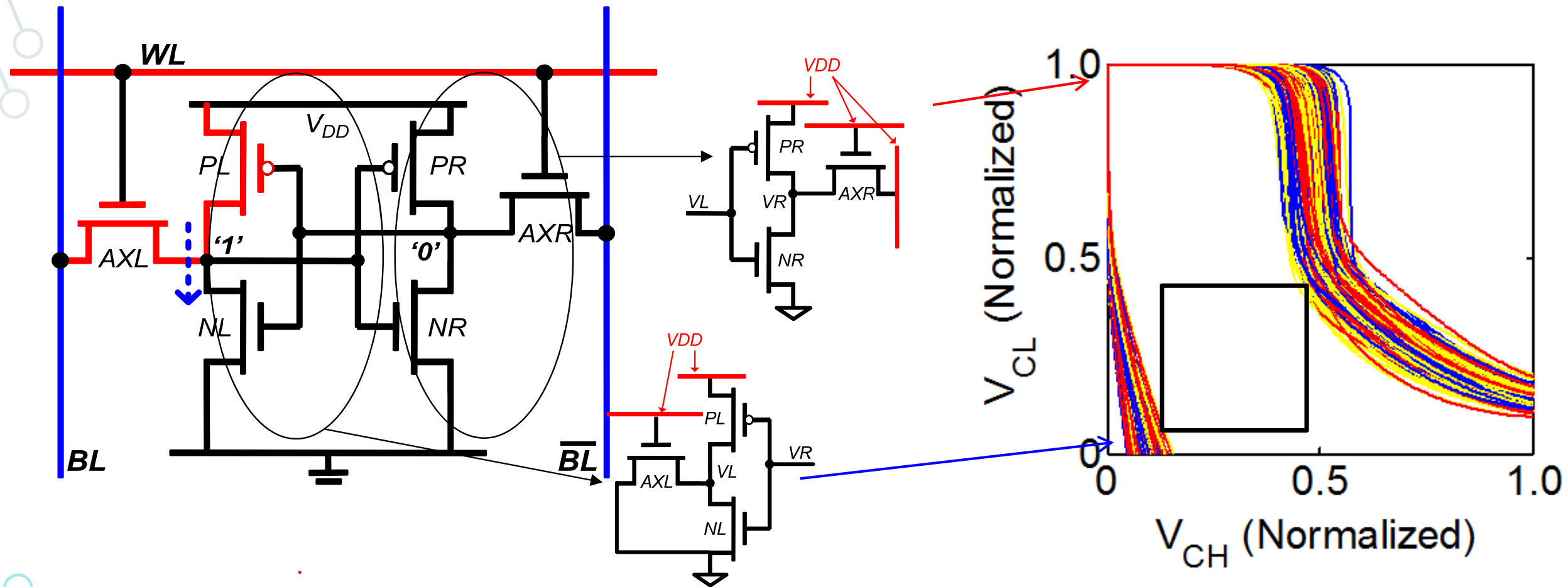
# Read Stability – N-Curve



- A, B, and C correspond to the two stable points A and C and the meta-stable point B of the SNM curve
- When points A and B coincide, the cell is at the edge of stability and a destructive read can occur

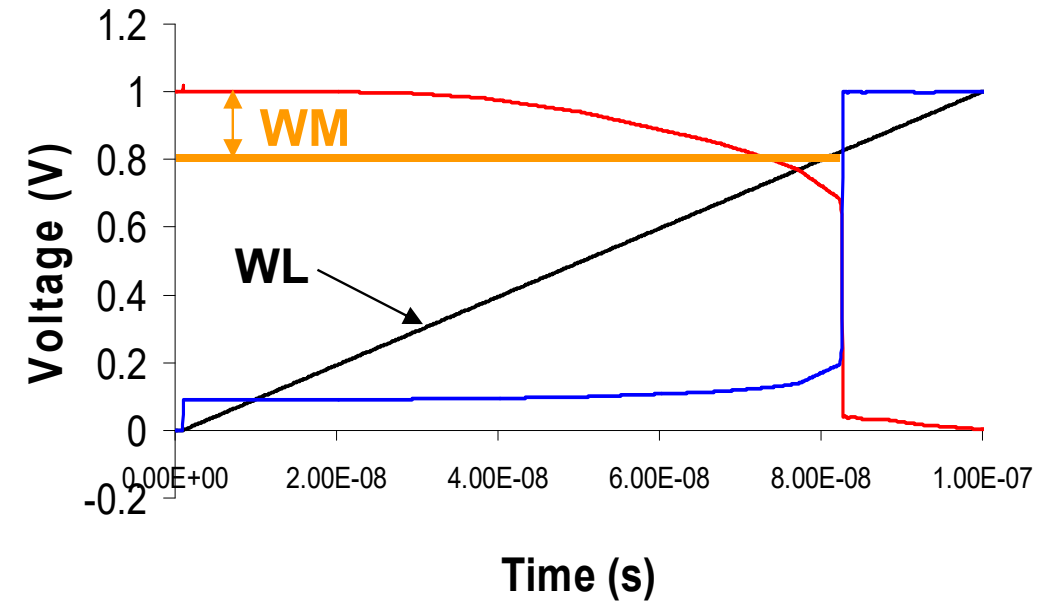
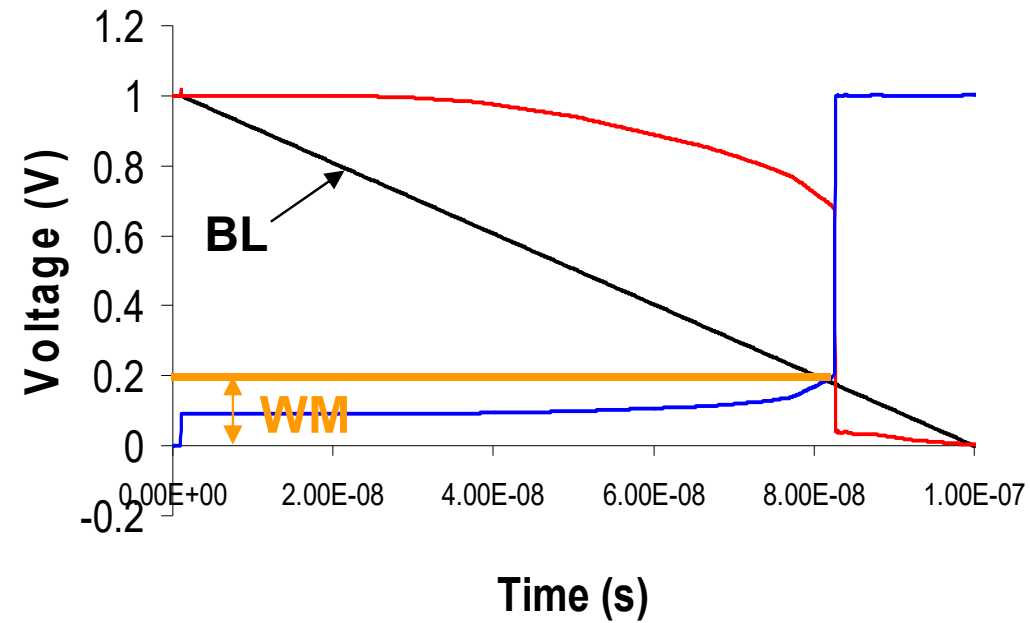
Grossar, JSSC'06

# Write Stability – Write Noise Margin (WNM)



- Writeability is becoming harder with scaling
- Optimizing read stability and writeability at the same time is difficult

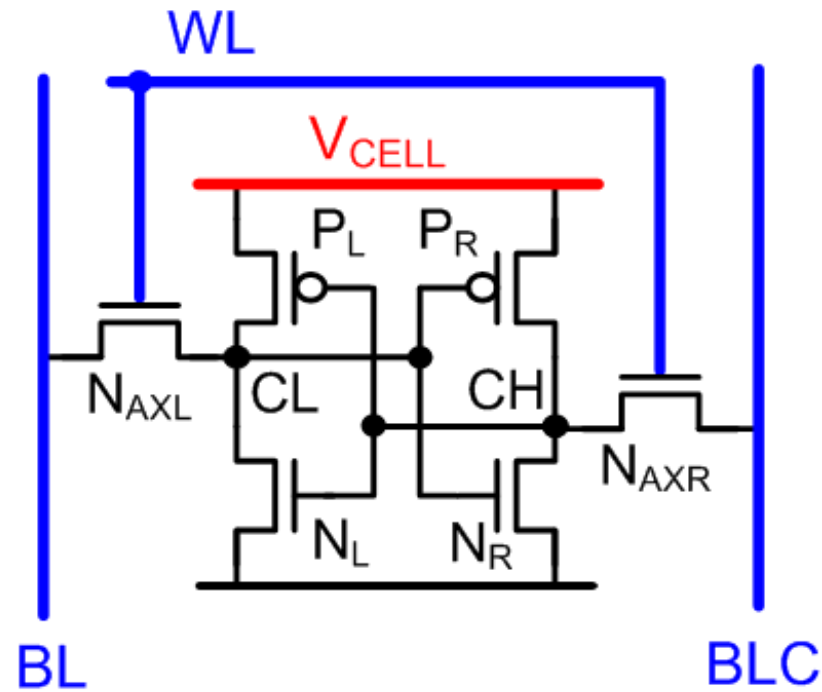
# Writeability – BL/WL Write Margins



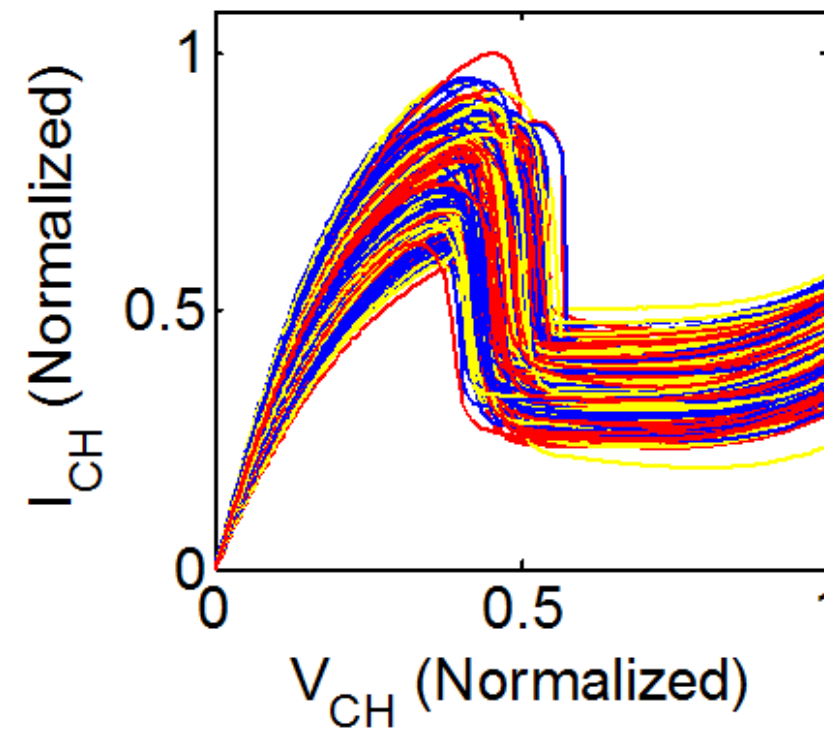
- Highest BL voltage under which write is possible when BLC is kept precharged

- Difference between VDD and lowest WL voltage under which write is possible

# Write Stability – Write Current (N-Curve)

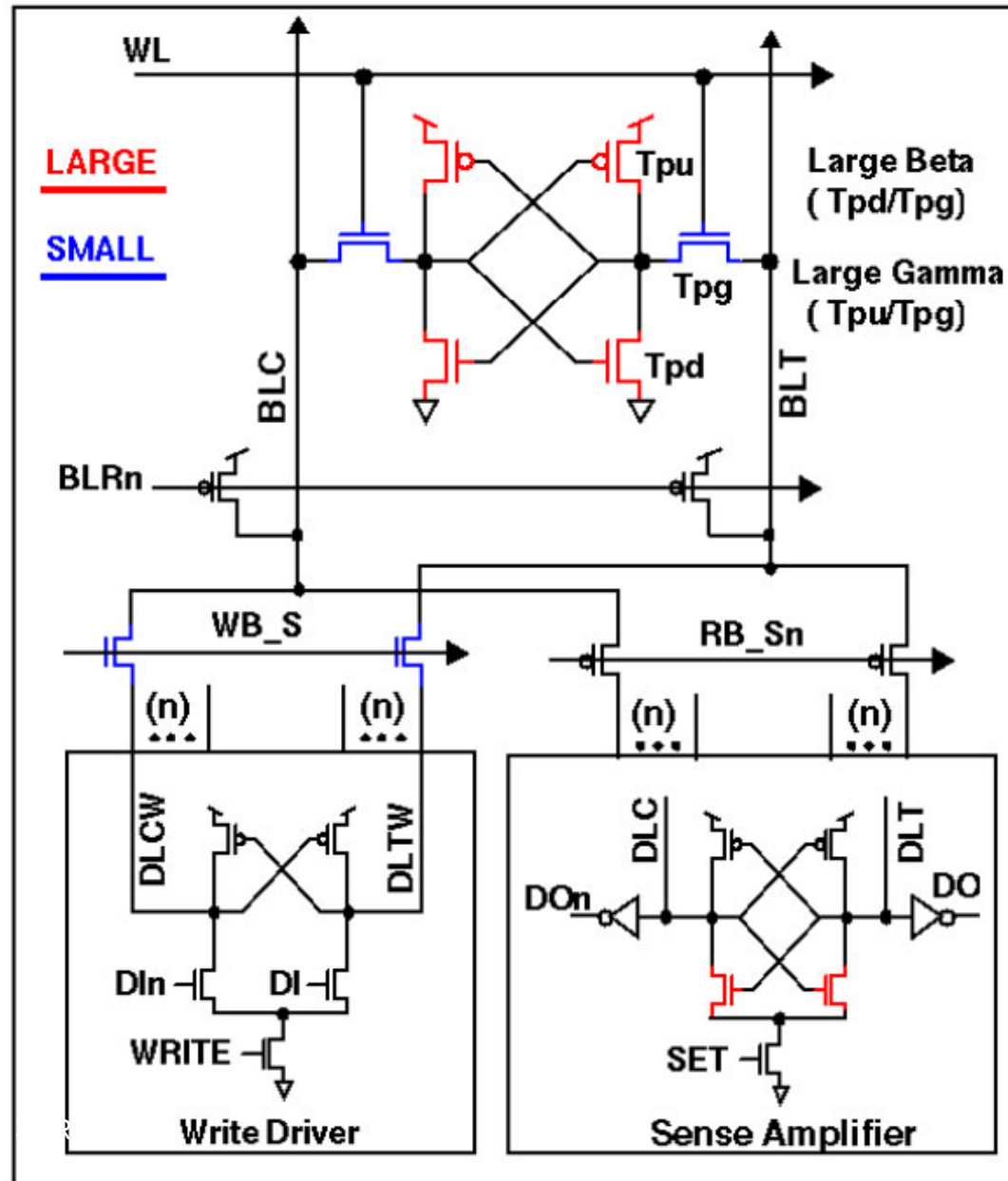


- Minimum current into the storage node

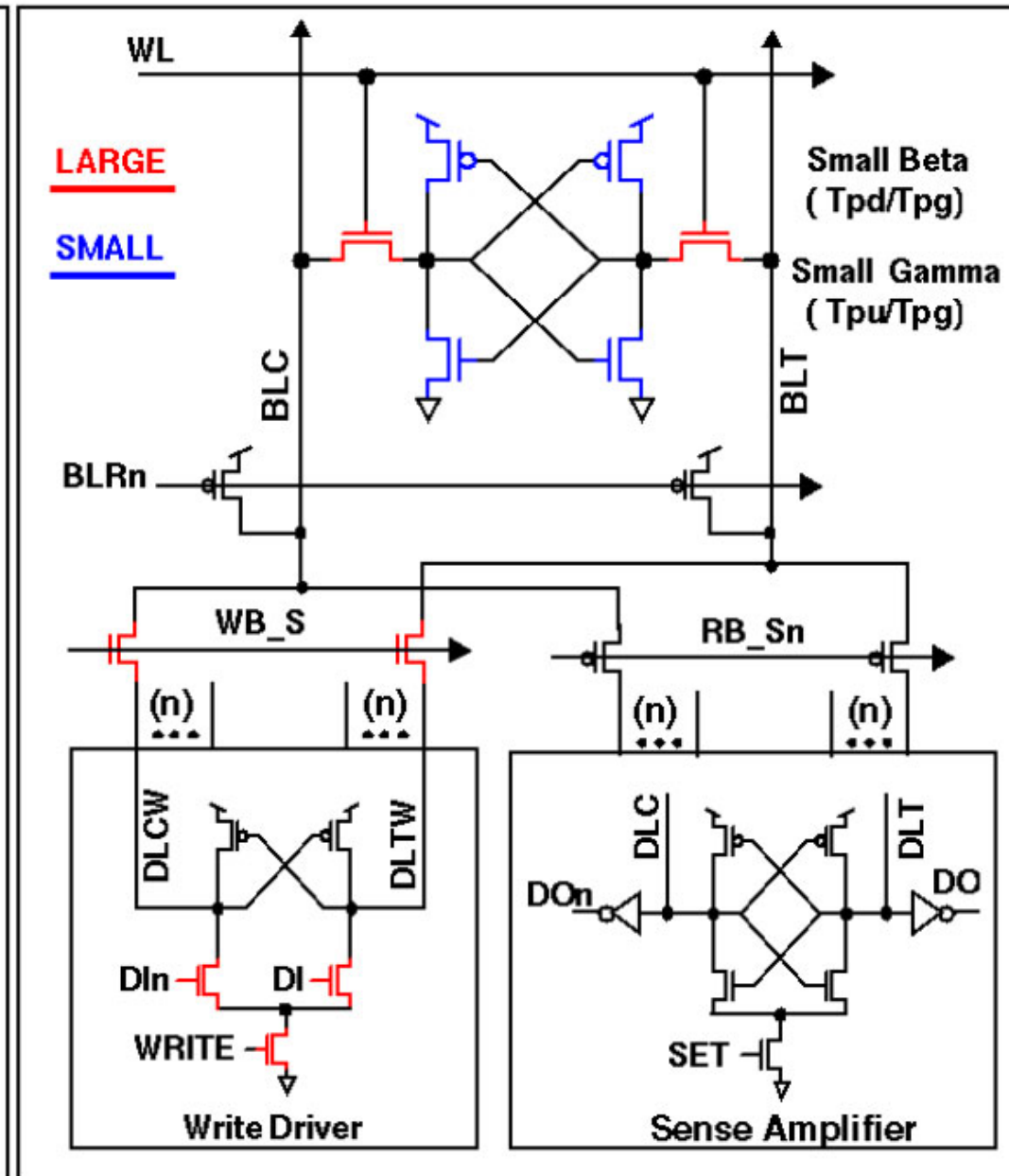


# The Conflict Between Read and Write

READ - OPTIMIZED SYSTEM



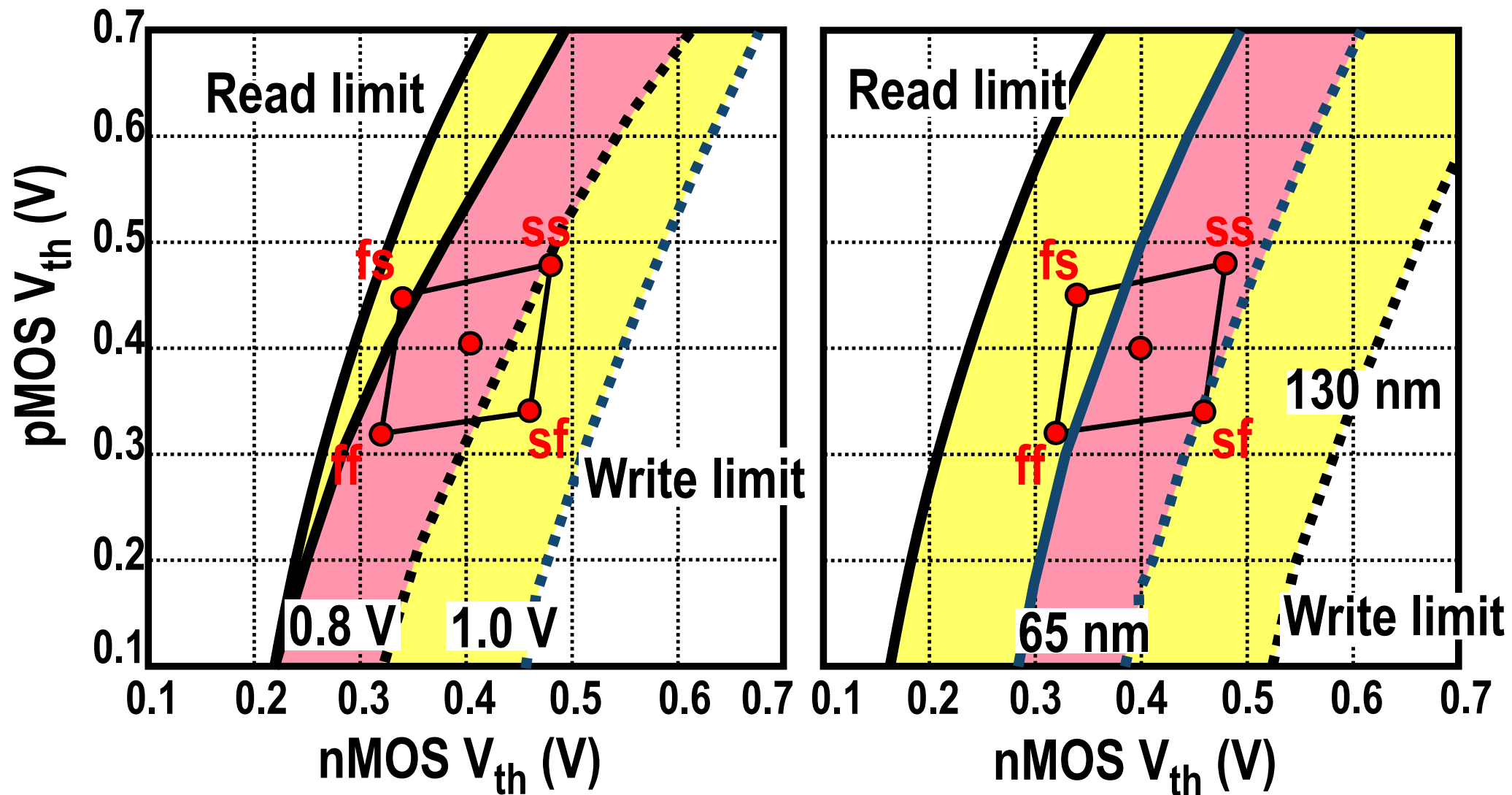
WRITE - OPTIMIZED SYSTEM





# $V_{Th}$ Window

- Assuming global spread

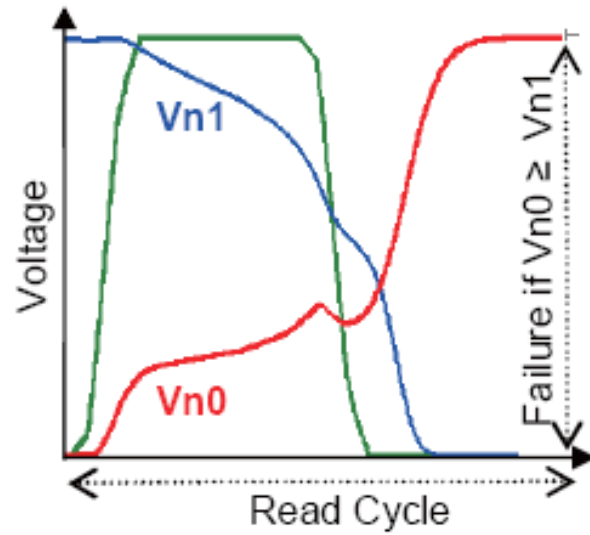


Yamaoka, ISSCC'05

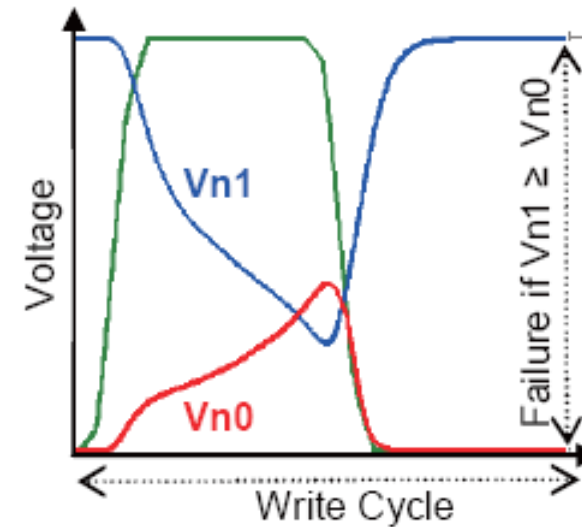


## 4.D Dynamic Margins

# 6-T SRAM Static/Dynamic Stability



(a) read failure criterion



(b) write failure criterion

- Read Margin

- SNM: pessimistic

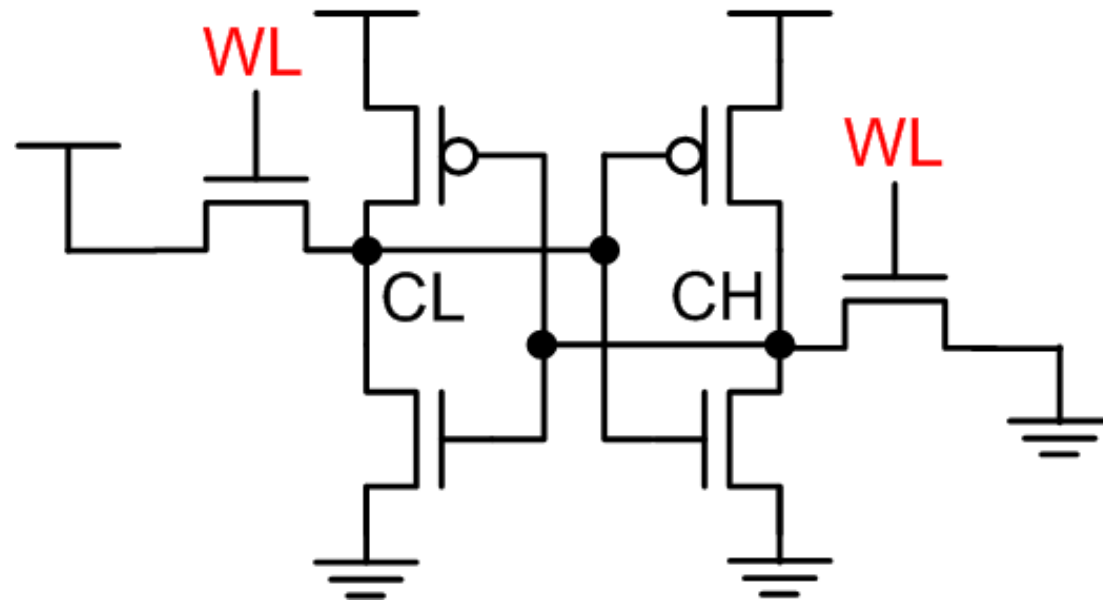
- Write Margin

- WNM: optimistic

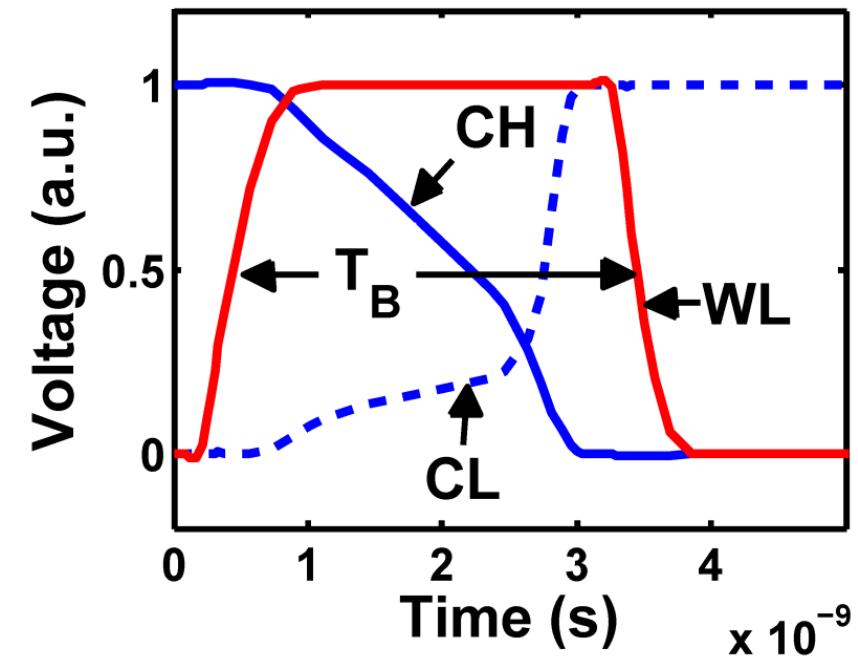
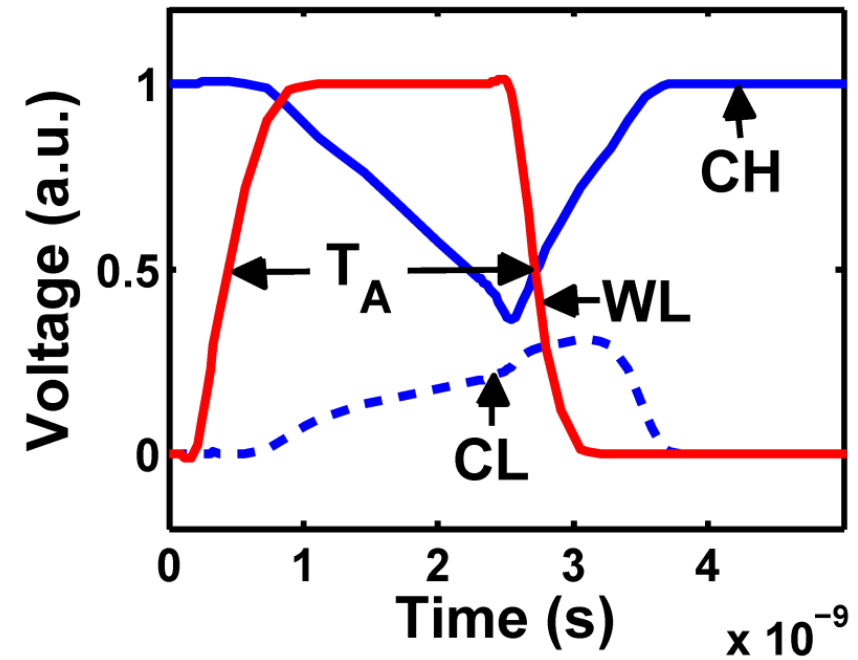
- Introduction to dynamic margins

- Three failure modes: read stability, writeability and read access time

# Dynamic Write Stability

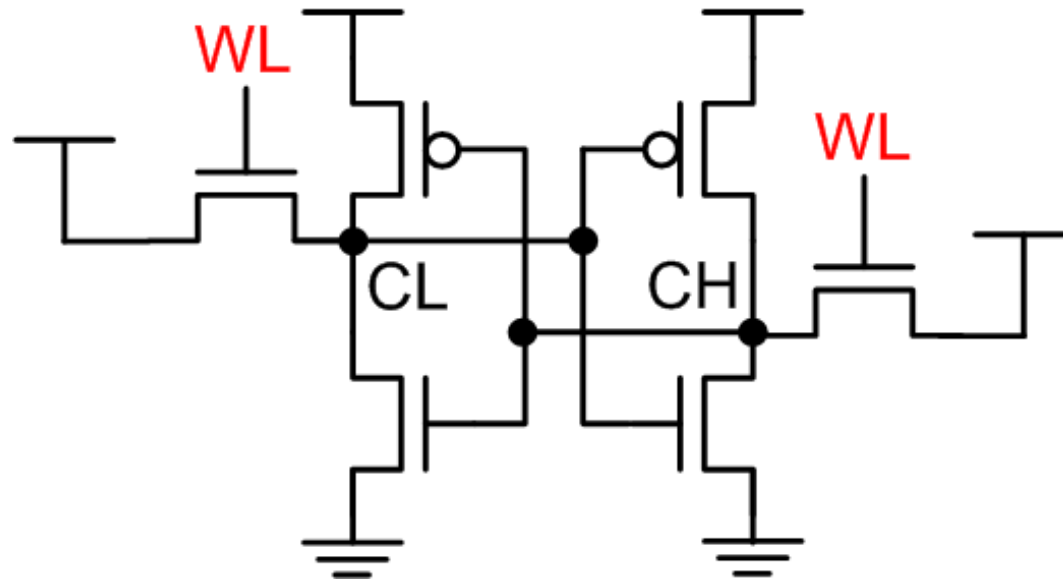


- $T_A < T_{\text{write}} < T_B$
- $T_{\text{write}} = \text{dynamic write stability}$
- Static margins are optimistic

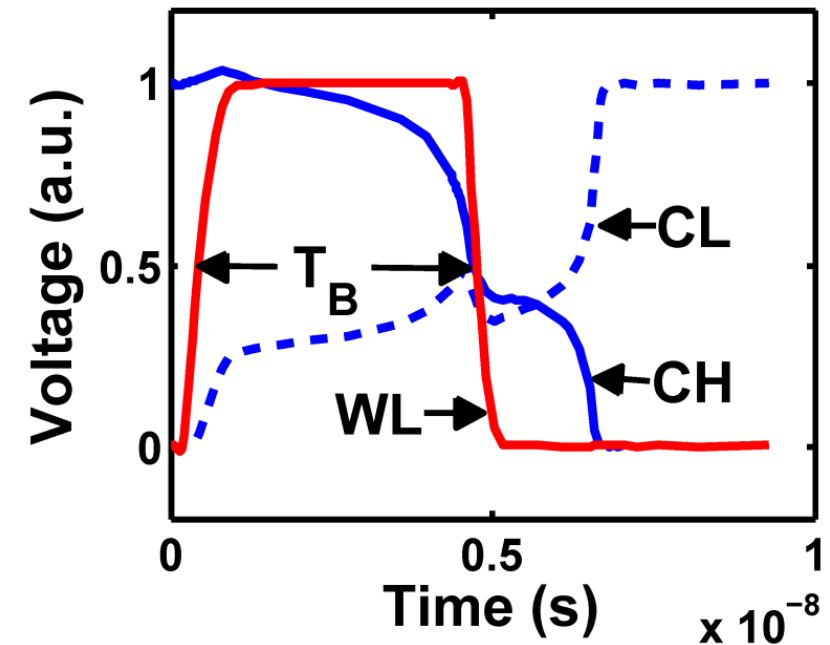
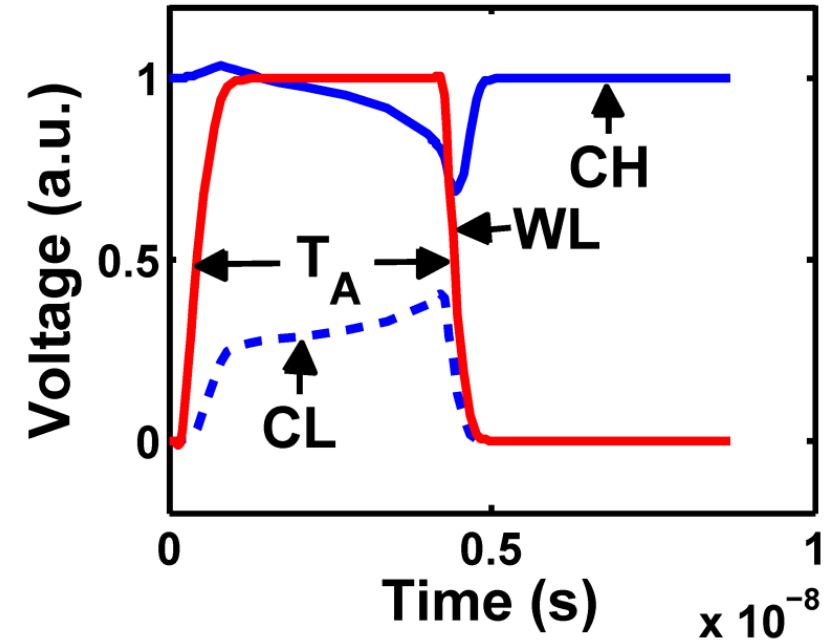


Khalil, TVLSI'08

# Dynamic Read Stability

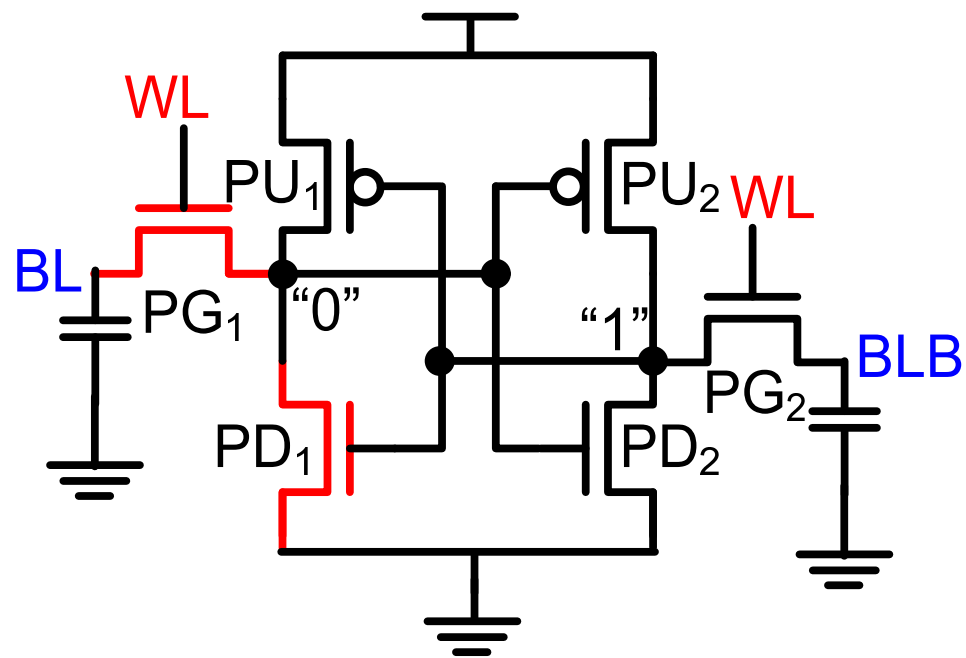


- $T_A < T_{\text{read}} < T_B$
- $T_{\text{read}} = \text{dynamic read stability}$
- Static margins are pessimistic

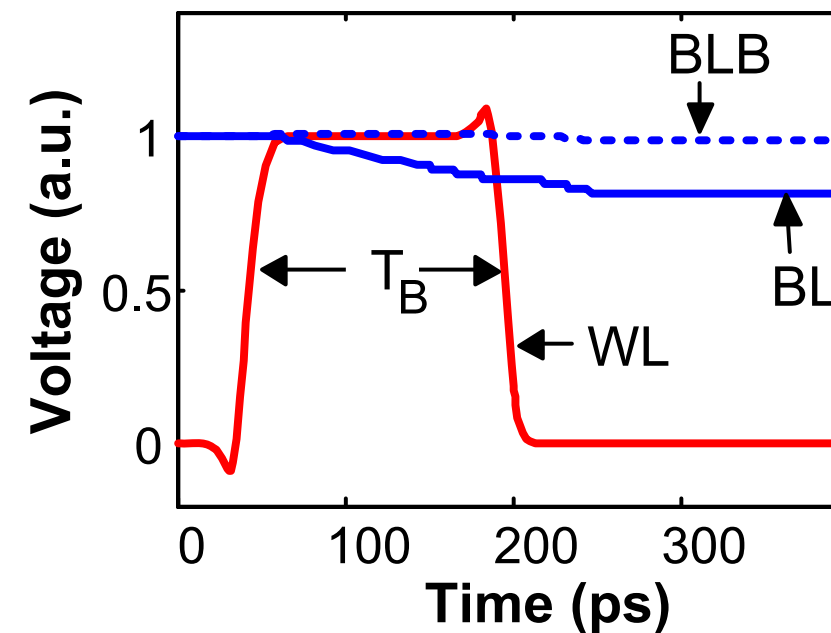
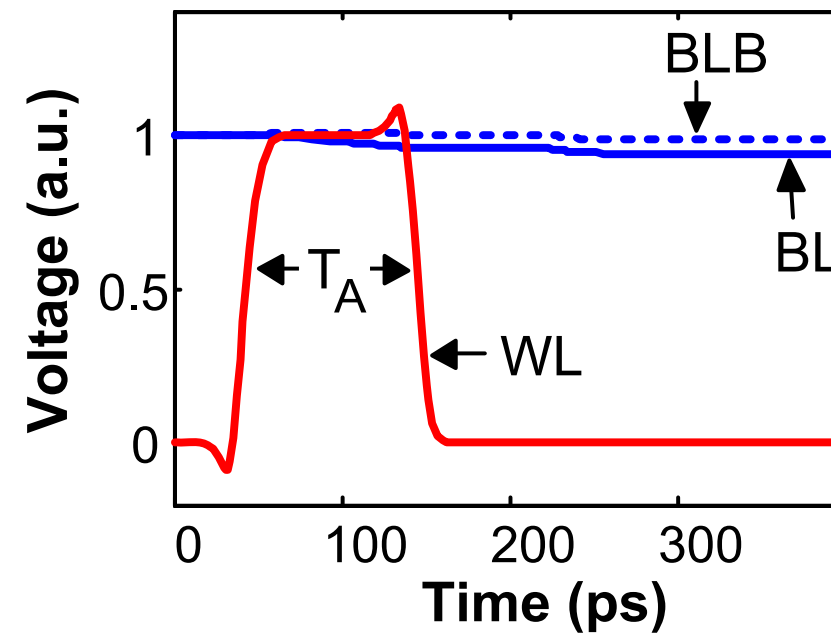


Khalil, TVLSI '08

# Dynamic Read Access



- $T_A < T_{\text{access}} < T_B$
- $PD_1$  and  $PG_1$  are critical

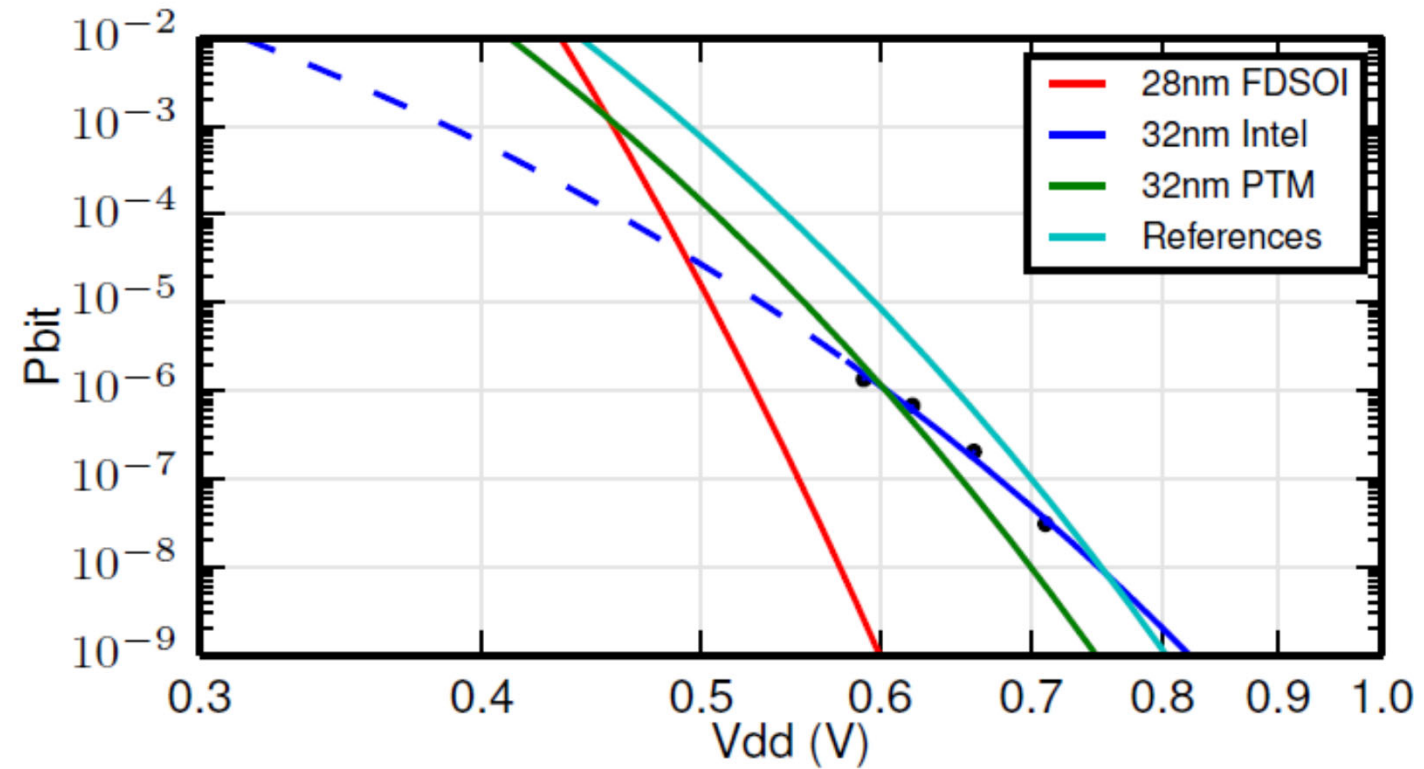


Khalil, TVLSI '08



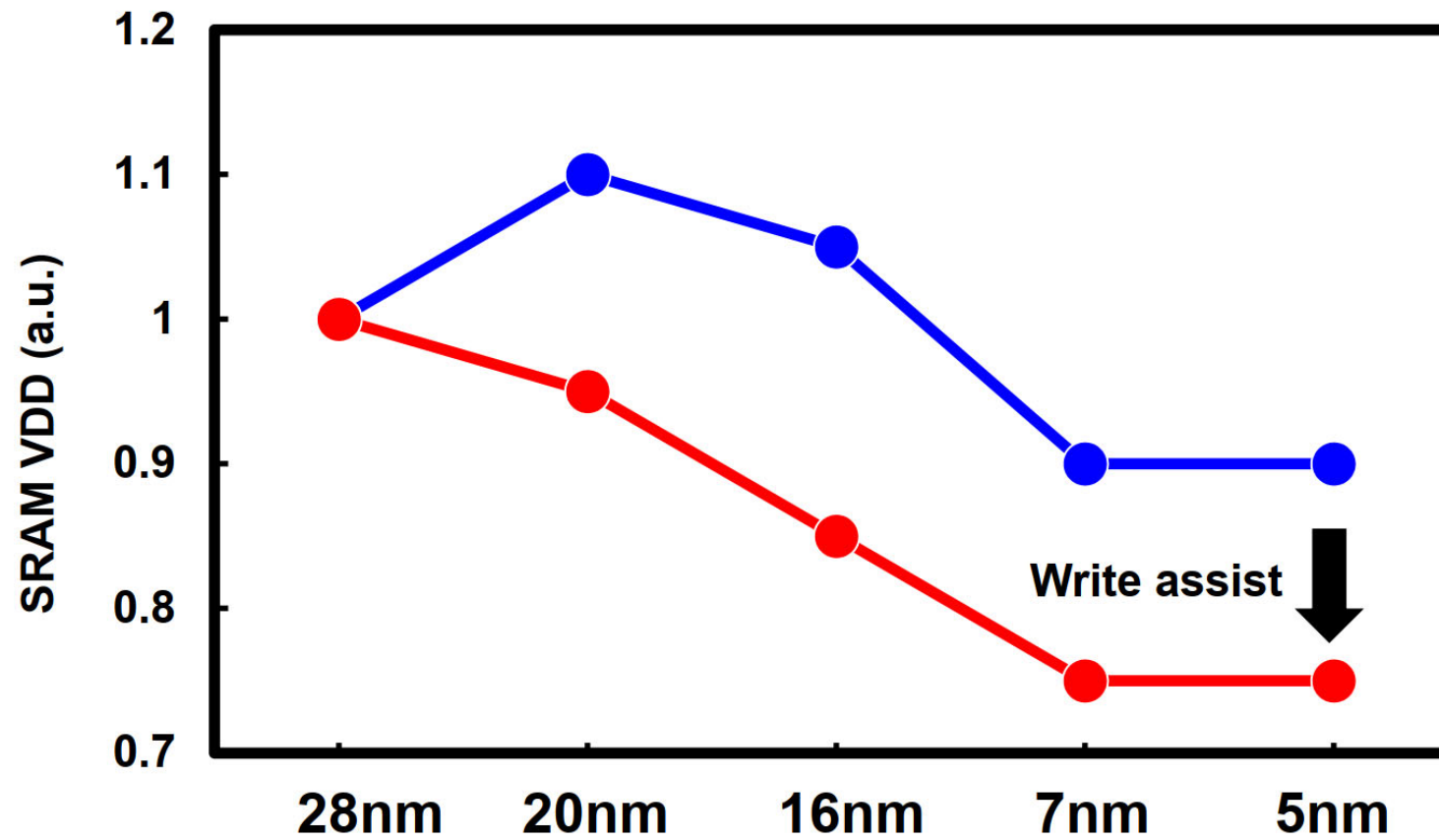
# SRAM Overall $V_{min}$

- Both read and write
- Some contradicting data



# SRAM Vmin Scaling Trend

- SRAM voltage often higher than logic



- J. Chang, ISSCC'20

## Next Lecture

- Peripheral circuits
- SRAM assist techniques
- Alternatives to 6T SRAM